

KEVIN QUINN
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SUMMARY

A problem solver with a unique skill of analyzing and quantifying complex situations, breaking them up into smaller components and developing fail proof solutions. These solutions include developing business processes, procedures and software. Has a deep passion for **web** and **automated test development**. Skills include the following

Web Development and QA

- * FrontEnd /Framework: HTML5, CSS3, JavaScript, React.js, Bootstrap
- * BackEnd /Framework: Node.js, Express
- * Database: MongoDB, MSSQL
- * Automated Test: Katalon Studio

Additional Software/Operating Systems

- * OOP: C#, C++
- * Scripting: Perl, Groovy
- * Operating Systems: Unix/Linux

Leadership, Communication and Mentoring

- * Coordinated worldwide test meetings which led to quicker release times with lower defects
- * Cross Functional technical representative for high volume Graphic DRAMs in production
- * Developed business processes to facilitate in bridging the gap between manufacturing teams
- * Implemented a system to track and improve test development

EXPERIENCE

KPQ SOLUTIONS; Stokesdale, NC

2019-Present

Owner Developed and deployed a variety of web applications which include the following:

- * Live Sports Tracker (www.ubci.info) A web application which displays live updates entered by a broadcaster who registers a sporting event
- * Coin Inventory Management (www.coininv.org) A web application to track all US coins
- * Static Website for an Insurance Adjustment company (www.bell-lewis.com)

QORVO; Greensboro, NC

2015-2019

Test Engineer, Mobile Department. Launched a new platform (Cohu DiamondX) to test IoT products. Developed all the firmware to program the IoT product using RFFE, SDE and UART protocols. Diligently, managed the efforts of production teams in China and Greensboro to ensure on time release.

MICRON TECHNOLOGY; Manassas, VA

2009-2015

Test Engineer, DRAM Department. Implemented a solution which increased the manufacturing yield of DRAM products by over 2%. Developed analysis tools to facilitate engineers in identifying yield loss. Published in Micron's Technology Journal for developing and implementing a new solution to increase the manufacturing yields. Led, transferred and communicated the testing solution of a new technology which increased the throughput of products tested by 50%.

QIMONDA; Williston, VT and Sandston, VA

2003-2009

Product and Test Engineer, Memory Department. Led and mentored a team of nine engineers. Initiated test guidelines which led to a 75% reduction in program errors while reducing the program release time by 50%. Spearheaded engineering efforts which decreased customer returns by over 500%, and increased yield over 10%.

EDUCATION

B.S in Electrical Engineering; Clarkson University; Potsdam, NY

PATENTS

- * Patent (Number 5545934) titled "Voltage Clamp Circuit"
- * application (number 20070200571) titled "Verifying Individual Probe Contact Using Shared Tester Channels"
- * Patent application (number 20090225610) titled " Integrated Circuit That Selectively Outputs Subsets of a Group of Data Bits"

PUBLICATIONS & SEMINARS

- * Co-author of a paper published in Micron's Technical Journal, titled "Introduction to Yield Simulation Using Bitmap Defect Data"
- * Delivered a seminar to all the site engineers, summarizing all the Semiconductor Test and Quality topics in Micron's Technical Journal

SOCIAL MEDIA

Business: www.kpqsol.com

Portfolio: www.kquinn.info

LinkedIn: www.linkedin.com/in/kevinquinn1918

GitHub: www.github.com/kquinn3